## Notice of References Cited Application/Control No. 10/576,685 Reexamination NAGANO ET AL. Examiner SPENCER PATTON Applicant(s)/Patent Under Reexamination NAGANO ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,977,630 B1	12-2005	Donath et al.	345/7
	В	US-			
	O	US-			
	ם	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	JP 09287960 A	11-1997	Japan	MATSUOKA et al.	G01C 21/00
	0	JP 10269495 A	10-1998	Japan	YOKOSHIMA, KATSUHIKO	G08G 01/0962
	Р	JP 2000211452 A	08-2000	Japan	NINAGAWA, YUJI	B60R 21/00
	Ø					
	R					
	Ø					
	Η					

## NON-PATENT DOCUMENTS

	NON-FAILNI DOCUMENTO						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	x						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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